


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/672,200	PARIKH ET AL.	
	Examiner	Art Unit	
	Huyen Le	3751	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
401		183			401	261	25	195	
INTERNATIONAL CLASSIFICATION					604	3			
B	4	3	M	11/06					
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<i>Huyen Le</i> Huyen Le 3/1/2006 (Assistant Examiner) (Date)		<i>Justin Z</i> 3/3/06 JUSTINE R. YU SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Priamry Examiner) (Date)		Total Claims Allowed: 1 O.G. Print Claim(s) 1 O.G. Print Fig. 1	
<i>Nicole P. Pineda</i> 3-3-06 (Legal Instruments Examiner) (Date)					

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant					<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
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